

2.2 Lensless imaging and synchrotron physics

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# Lensless imaging – general considerations





# **Lensless imaging and SAXS**



- Also "coherent x-ray diffractive imaging" CXDI
- Coherent illumination of sample
- Transverse (spatial) coherence

$$l_c^{(t)} = \frac{\lambda}{2\Delta\theta} = \frac{\lambda R}{2D}$$

- Lensless-imaging beamlines
  - Long source–sample distance (R)
  - Small source size (D)
  - Highly collimated beam ( $\theta$ )
  - Transverse coherence length ~ 200 1000  $\mu m$
  - Minimize optical elements that disrupt wavefront
- DLSRs: increase in coherent flux ~  $10^3 10^4$ !!

# **Lensless imaging and SAXS**



- Diffraction pattern
  - Noncrystalline samples
    - In forward-scattering direction only
  - Crystalline objects
    - Convolution of diffraction pattern due to periodicity and 'shape function' defining boundary of object
    - ⇒ regular array of replicas of same pattern
    - Bragg-CXDI

#### **Lensless imaging vs SAXS**



Ensemble of n identical spheres



$$I = \sum_{n} |\mathcal{F}(\text{sphere})|^{2}$$
$$= n |\mathcal{F}(\text{sphere})|^{2}$$

$$I = |\mathcal{F}(\text{ensemble of } n \text{ spheres})|^2$$

Interference between scattering from individual scatterers



# **Speckle**



Progression of speckle pattern for increasing ensemble of identical spheres with constant average areal density

# **Speckle**



# **Lensless imaging and DLSRs**



- Signal strength  $\propto 1/Q^4 \simeq 1/\theta^4$
- 10<sup>4</sup> increase in coherent flux ⇒ x 10 increase in resolution ~ nm or smaller
- Sample manipulation accuracy becomes impossible
  - Becomes less competitive with e.g., electron imaging
- Exploit higher flux otherwise
  - Faster scanning
  - Higher photon energies
    - Less integrated dose
    - Larger penetration depths



#### **Nyquist frequency**



Creative Commons: https://en.wikipedia.org/wiki/Aliasing#/media/File:FFT aliasing 600.gif

 Sampling frequency ≥ 2 x highest frequency contained in the signal

 $f_s \ge 2f_c$ 

 For a given *f<sub>s</sub>*, the maximum frequency you can accurately represent without aliasing is the Nyquist frequency. The Nyquist frequency equals one-half the sampling frequency

$$f_N = fs/2$$

"Aliasing": when

$$f_s < 2f_c$$

#### **Oversampling**

Measuring spatial frequency

 $f_s > f_N$ 



# Redundancy

- Additional information/constraints beyond raw scattering data
  - Sparsity of real-space object such as atomicity
  - Physical extent of object
    - "Shrink-wrap"
  - Positivity of scattering (electron) density
  - Symmetry considerations
  - Consistency in overlapping illuminated regions (e.g., in ptychography)

• ...

Narrows down possible solutions



# **Coherent x-ray diffractive imaging**

# **Coherent x-ray diffractive imaging**



Animations courtesy I. Mochi, Swiss Light Source

CXDI (or CDI)

Also 'lensless imaging'

Diffraction pattern

Noncrystalline sample

In forward-scattering direction only

Crystalline objects

Regular array of replicas of same pattern

Bragg-CXDI

 Oversampling determined by size of coherently illuminated sample

Smaller samples ⇒ larger features

 Phase problem resolved typically via phaseretrieval algorithms

Gerchberg-Saxton (error reduction)

Hybrid input-output (Fienup)

Difference-map

• ...

See V. Elser https://opg.optica.org/josaa/abstract.cfm?URI=josaa-20-1-40

# **Coherent x-ray diffractive imaging**



See also H.N. Chapman and K.A. Nugent https://www.nature.com/articles/nphoton.2010.240 XRD

- Samples have translational symmetry
- Record far-field scattering (diffraction) pattern
- Regain real-space structure through IFT
  - Phase problem
- Unit cells  $\lesssim 200 \text{ Å}$
- Resolution  $\lesssim Å$
- CXDI
  - Same principle as XRD
  - Samples can be crystalline or noncrystalline
    - Scattering pattern: "speckle"
    - Sizes up to ~ μm
    - Requires sample < coherence volume of SR</li>
    - Big improvements with DLSRs!!
    - Resolution down to ~ 10 nm



- CXDI in forward-scattering direction
  - Used for noncrystalline samples
  - Sample bathed in coherent x-rays
    - Limits sample size
  - Requires rotation of sample at least by 180°, or even 360° if close to an absorption edge (scattering pattern loses its centrosymmetry – this doubling of information contributes to redundancy)

# **Bragg CXDI – a perfectly regular starry firmament**



Perfect large crystal x Nanosized volume = Nanocrystal

#### **Bragg CXDI – a perfectly regular starry firmament**

# $\mathcal{F}(A \times B) = \mathcal{F}(A) \otimes \mathcal{F}(B)$

#### **Bragg CXDI – a perfectly regular starry firmament**



Diffraction pattern of large crystal 🚫 Shape function

Diffraction pattern of nanocrystal

# **Bragg CXDI**





#### Rotation angles ~ few degrees

# **Applications of Bragg CXDI**





- Phase information arises from strains within the crystal
  - ⇒ Bragg CDI yields high resolution 3-D images of strain from within a nanocrystal in direction of Q
- Bragg diffraction away from (000) direction
  - ⇒ scattering object does not need to be physically isolated
  - Nonperiodic substrates or those with different lattice constants will be invisible to the diffraction process
  - ⇒ use Bragg CXDI to study the impact of an interface with the nanocrystal
- Several different Bragg spots (different Qs)
  - $\Rightarrow$  3-D strain tensor within nanocrystal

M.A. Pfeifer et al., Nature 442, 63-66 (2006) https://www.nature.com/articles/nature04867

# **Ptychography**

# **Role of ptychography**



- Bridge resolution gap between full-field tomographies and XRD/electron microscopy
- Scanning aspect allows high resolution down to few nm on extended samples with macroscopic dimensions limited only by IT considerations (and absorption lengths, not normally a problem for HXR)
- Spatial resolution determined by
  - Largest scattering angle
  - Stability of sample movements
  - NOT by size of illumination or step size

# **The perfect marriage**



# **CXDI** vs ptychography



Sample flooded with coherent radiation:

 $l_c^{(t)} > a$ 

- Speckle and oversampling determined by sample size a
- Redundancy provided by
  - Positive electron density
  - Approximate maximum/minimum electron densities
  - Overall sample size (if known)

# **CXDI vs ptychography**



- Extended sample
  - Larger than  $l_c^{(t)}$
  - Part of sample illuminated with coherent radiation
- Speckle and oversampling determined by illumination size  $l_c^{(t)}$
- Raster sample with step sizes <  $l_c^{(t)}$ 
  - Marriage of CXDI and STXM
- Redundancy (real-space constraint) provided by
  - Overlap between adjacent recordings – solutions must be the same in real-space



# **Experimental considerations in ptychography**



- HXR: ~ 0.5 2 Å
- SXR: near absorption edges e.g., magnetic materials
  - L-edges 600 900 eV
- Size of illumination ~  $\mu m$
- Depth of field\* T ~  $5(\Delta x)^2/\lambda$ 
  - $\Delta x = desired resolution$
  - $\Rightarrow$  T ~ 1 10  $\mu$ m for HXR and 10-nm resn.
- Optimal areal overlap<sup>†</sup> between adjacent illuminations ~ 60 – 80%
- Nested iteration to determine (imperfect) incident wavefront<sup>‡</sup>
- DLSRs: increase in coherent flux ~ 10<sup>3</sup>!!

\*M. Holler *et al.*, Sci. Rep. **4** 3857 (2014)
<sup>†</sup>O. Bunk *et al.*, Ultramicroscopy **108** 481 (2008)
<sup>‡</sup>P. Thibault *et al.*, Ultramicroscopy **109** 338 (2009)

#### **Experimental considerations in ptychography**



Overlap = 
$$\frac{2}{\pi} \arccos\left(\frac{\Delta}{2}\right) - \frac{\Delta}{2\pi}\sqrt{1 - (\Delta/2)^2}$$

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# **Sample manipulation**



- Sample illumination accuracy better than desired spatial resolution
  - Optics (FZP, OSA, pinhole, etc) fixed
  - Sample controlled movements
  - Both x- and y-directions
- Interferometric control using lasers
- Avoid long-term drift
  - Especially problematic in cryogenically cooled samples
- In case of ptychographic tomography (PXCT, see next video) rotation control also required
  - Axis wobble

\*M. Holler et al., Sci. Rep. 4 3857 (2014)

#### **Ptychographic tomography**



- PXCT combines
  - Ptychography
  - Tomography
- 3D reconstruction with ~ few 10s nm resolution
  - Ptychographic 2D reconstructions at different projection angles
  - Tomographic 3D reconstruction from ptychographic reconstructions
- Density variations < 1% possible</li>

# **Ptychographic laminography**



- Used for extended samples in two dimensions (flat objects)
  - Sample rotation axis *r* tilted relative to *x-y* plane perpendicular to incident radiation (tomography)
  - Also scan sample laterally (ptychography)

 Offset angle means some of reciprocal space cannot be accessed



**PyXL** 

#### **Example – nondestructive study of chip architecture**



- PyXL @ 6.2 keV
- Tilt angle off vertical  $\theta = 61^{\circ}$
- Integrated circuit chip with 16-nm fin fieldeffect transistor technology
- Size of radiation on sample T = 4  $\mu$ m
- Number N of angular projections between 0 and 360° = 2872
- Theoretical resolution

$$\Delta r = \pi rac{T}{N} an heta$$
 = 7.6 nm

Actual resolution 19 nm



#### From scalar to vector to tensor



- "Standard" CXDI, ptychography, laminography yield scalar properties for each voxel
  - e.g., electron density
- Progress to directional properties in each voxel
  - Magnetic direction
  - Piezoelectricity
  - ...
- Tensor properties within a voxel also possible
  - Full 3D spatial distribution of given property within voxel

# **Vector PXCT – nanomagnetism**

# 





- 3D study of nanoscale magnetic materials
  - Basic research
  - Spintronics
  - Storage
  - Energy-harvesting industry
- Transmission electron microscopy
  - Limited to depths < 10 nm</li>
- SXR microscopy
  - Limited to depths < 20 nm</li>
- HXR transmission to many microns
  - GdCo<sub>2</sub>
  - L-edge of Gd @ ca. 7.2 keV

# **Vector PXCT – magnetism**



- GdCo<sub>2</sub> pillar, 5 μm diameter
  - Rotate and scan x- and y-directions
- Circular polarized x-rays sensitive to component of magnetization in the propagation direction
- Rotating the sample therefore changes the absorption coefficient
  - ⇒ domain contrast
  - In contrast to standard absorption in lensless imaging





# **Vector PXCT – magnetism**





C. Donnelly et al., Nature 547 328 (2017)

- "Magnetic vortices" form when electron spins swirl in a circle within a plane
  - At the centre of the circle, swirl becomes tighter and tighter – "Bloch point"
  - Eventually magnetization at the core tilts out of the plane
  - Prior to this work, magnetic vortices widely studied in 2D systems, but remained only a theoretical prediction in 3D
- Vortices shown to be surprisingly stable to both temperature and externally applied magnetic fields
  - Stability thought to be provided by pinning to domain walls

#### **Scanning SAXS tensor tomography**



SSTT

- In each voxel (x, y, z) study a tensor property
  - Physical size
  - Intensity distribution
- Requires six degrees of freedom

# **SAXS tensor tomography**



- $I(\theta,\phi,x_s,y_s,x_d,y_d)$ 
  - Tensor property
- Within a given voxel @ (x,y,z)
  - I(Q,θ,φ)
- Detector sees integrated signal of all voxel contributions along direction of propagation
  - Separate using tomographic methods

#### **SAXS tensor tomography**



Image: Inigo.quilez Creative Commons

- Any distribution I(θ, φ) can be described as a linear combination of spherical harmonics Y<sup>m</sup>
- Angular distribution of intensity of given Q-value(s) associated with certain SAXS features
  - e.g., 65-nm signal of mineralized parts of collagen fibrils



Voxel

#### **SAXS** tensor tomography – example: down to the bone



- Biology
  - Principle of hierarchical ordering
  - Maximize functionality
    - Strength
    - Robustness
  - Minimize weight and energy cost
  - Bone
    - Multiple length scales
      - Collagen molecules (nm)
      - Microfibrils
      - Fibrils
      - Lamellae
      - Osteons (mm)

# **SAXS tensor tomography – example**







- Human trabecular (spongy) bone
- Pencil beam  $\phi$  = 25  $\mu$ m
- Concentrate on 65-nm feature of mineralized collagen microfibrils
- > 10<sup>6</sup> SAXS patterns
  - Reconstruct 3D reciprocal-space map for each voxel
  - Model using spherical harmonics
    - Provides representation of nanoscale structure distribution
  - From reconstruction
    - Main ultrastructure orientation depicted by orientation of the cylinder
    - Degree of orientation the orientation of the cylinder illustrated by
      - Colour: indicating the ratio of anisotropic scattering to total scattering
      - Length of the cylinders: total scattering intensity

# **SAXS tensor tomography – example**



